

Notice of References Cited

Application/Control No.

10/065,816

Applicant(s)/Patent Under
Reexamination
HARDWICKE ET AL.

Examiner

Gail Verbitsky

Art Unit

2859

Page 1 of 1

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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